

TC74HCT00AP, TC74HCT00AF, TC74HCT00AFN

Quad 2-Input NAND Gate

The TC74HCT00A is a high speed CMOS 2-INPUT NAND GATE fabricated with silicon gate C²MOS technology.

It achieves the high speed operation similar to equivalent LSTTL while maintaining the CMOS low power dissipation.

This device may be used as a level converter for interfacing TTL or NMOS to High Speed CMOS. The inputs are compatible with TTL, NMOS and CMOS output voltage levels.

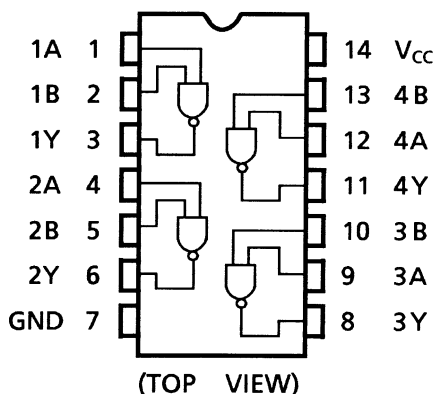
The internal circuit is composed of 3 stages including buffer output, which provide high noise immunity and stable output.

All inputs are equipped with protection circuits against static discharge or transient excess voltage.

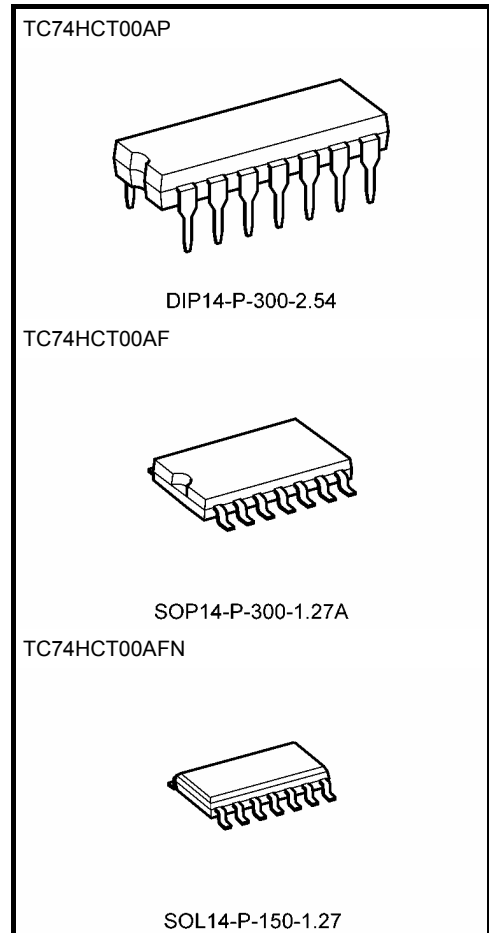
Features

- High speed: $t_{pd} = 10 \text{ ns}$ (typ.) at $V_{CC} = 5 \text{ V}$
- Low power dissipation: $I_{CC} = 1 \mu\text{A}$ (max) at $T_a = 25^\circ\text{C}$
- Compatible with TTL outputs: $V_{IH} = 2 \text{ V}$ (min)
 $V_{IL} = 0.8 \text{ V}$ (max)
- Wide interfacing ability: LSTTL, NMOS, CMOS
- Output drive capability: 10 LSTTL loads
- Symmetrical output impedance: $|I_{OH}| = I_{OL} = 4 \text{ mA}$ (min)
- Balanced propagation delays: $t_{pLH} \approx t_{pHL}$
- Pin and function compatible with 74LS00

Pin Assignment



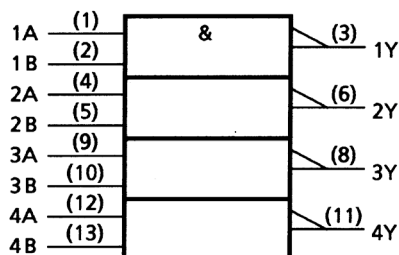
Note: xxxFN (JEDEC SOP) is not available in Japan.



Weight

DIP14-P-300-2.54	: 0.96 g (typ.)
SOP14-P-300-1.27A	: 0.18 g (typ.)
SOL14-P-150-1.27	: 0.12 g (typ.)

IEC Logic Symbol



Truth Table

A	B	Y
L	L	H
L	H	H
H	L	H
H	H	L

Absolute Maximum Ratings (Note 1)

Characteristics	Symbol	Rating	Unit
Supply voltage range	V_{CC}	$-0.5 \sim 7$	V
DC input voltage	V_{IN}	$-0.5 \sim V_{CC} + 0.5$	V
DC output voltage	V_{OUT}	$-0.5 \sim V_{CC} + 0.5$	V
Input diode current	I_{IK}	± 20	mA
Output diode current	I_{OK}	± 20	mA
DC output current	I_{OUT}	± 25	mA
DC V_{CC} /ground current	I_{CC}	± 50	mA
Power dissipation	P_D	500 (DIP) (Note 2)/180 (SOP)	mW
Storage temperature	T_{stg}	$-65 \sim 150$	$^{\circ}\text{C}$

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc.).

Note 2: 500 mW in the range of $T_a = -40$ to 65°C . From $T_a = 65$ to 85°C a derating factor of $-10 \text{ mW}/^{\circ}\text{C}$ shall be applied until 300 mW.

Operating Ranges (Note)

Characteristics	Symbol	Rating	Unit
Supply voltage	V_{CC}	$4.5 \sim 5.5$	V
Input voltage	V_{IN}	$0 \sim V_{CC}$	V
Output voltage	V_{OUT}	$0 \sim V_{CC}$	V
Operating temperature	T_{opr}	$-40 \sim 85$	$^{\circ}\text{C}$
Input rise and fall time	t_r, t_f	$0 \sim 500$	ns

Note: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs must be tied to either V_{CC} or GND.

Electrical Characteristics

DC Characteristics

Characteristics	Symbol	Test Condition		Ta = 25°C			Ta = -40~85°C		Unit	
				V _{CC} (V)	Min	Typ.	Max	Min		Max
High-level input voltage	V _{IH}	—		4.5~5.5	2.0	—	—	2.0	—	V
Low-level input voltage	V _{IL}	—		4.5~5.5	—	—	0.8	—	0.8	V
High-level output voltage	V _{OH}	V _{IN} = V _{IH} or V _{IL}	I _{OH} = -20 μA	4.5	4.4	4.5	—	4.4	—	V
			I _{OH} = -4 mA	4.5	4.18	4.31	—	4.13	—	
Low-level output voltage	V _{OL}	V _{IN} = V _{IH} or V _{IL}	I _{OL} = 20 μA	4.5	—	0.0	0.1	—	0.1	V
			I _{OL} = 4 mA	4.5	—	0.17	0.26	—	0.33	
Input leakage current	I _{IN}	V _{IN} = V _{CC} or GND		5.5	—	—	±0.1	—	±1.0	μA
Quiescent supply current	I _{CC}	V _{IN} = V _{CC} or GND		5.5	—	—	1.0	—	10.0	μA
	I _C	Per input: V _{IN} = 0.5 V or 2.4 V Other input: V _{CC} or GND		5.5	—	—	2.0	—	2.9	mA

AC Characteristics (C_L = 15 pF, V_{CC} = 5 V, Ta = 25°C, input: t_r = t_f = 6 ns)

Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit
Output transition time	t _{TLH}	—	—	4	8	ns
	t _{THL}					
Propagation delay time	t _{pLH}	—	—	10	20	ns
	t _{pHL}					

AC Characteristics (C_L = 50 pF, input: t_r = t_f = 6 ns)

Characteristics	Symbol	Test Condition		Ta = 25°C			Ta = -40~85°C		Unit
				V _{CC} (V)	Min	Typ.	Max	Min	Max
Output transition time	t _{TLH}	—	4.5	—	8	15	—	19	ns
	t _{THL}		5.5	—	7	14	—	18	
Propagation delay time	t _{pLH}	—	4.5	—	13	19	—	24	ns
	t _{pHL}		5.5	—	12	17	—	21	
Input capacitance	C _{IN}	—	—	—	5	10	—	10	pF
Power dissipation capacitance	C _{PD} (Note)	—	—	—	19	—	—	—	pF

Note: C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

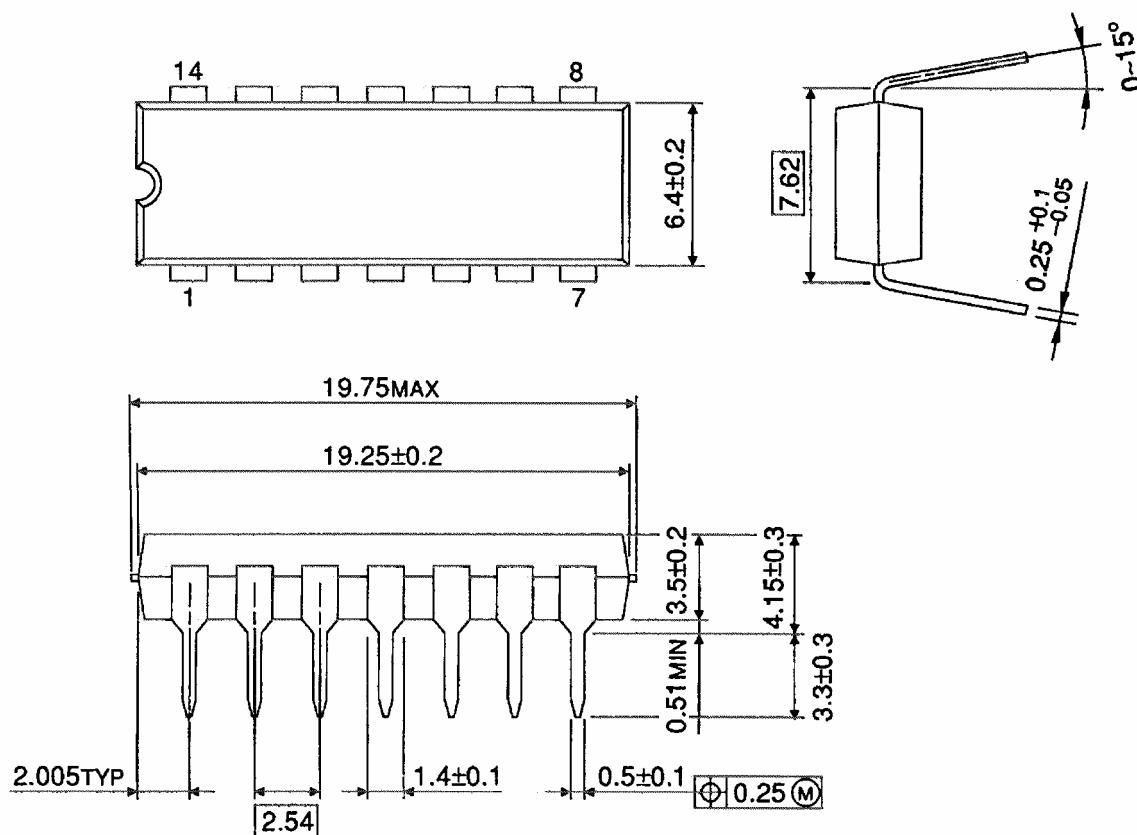
Average operating current can be obtained by the equation:

$$I_{CC}(\text{opr}) = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/4 \text{ (per gate)}$$

Package Dimensions

DIP14-P-300-2.54

Unit : mm

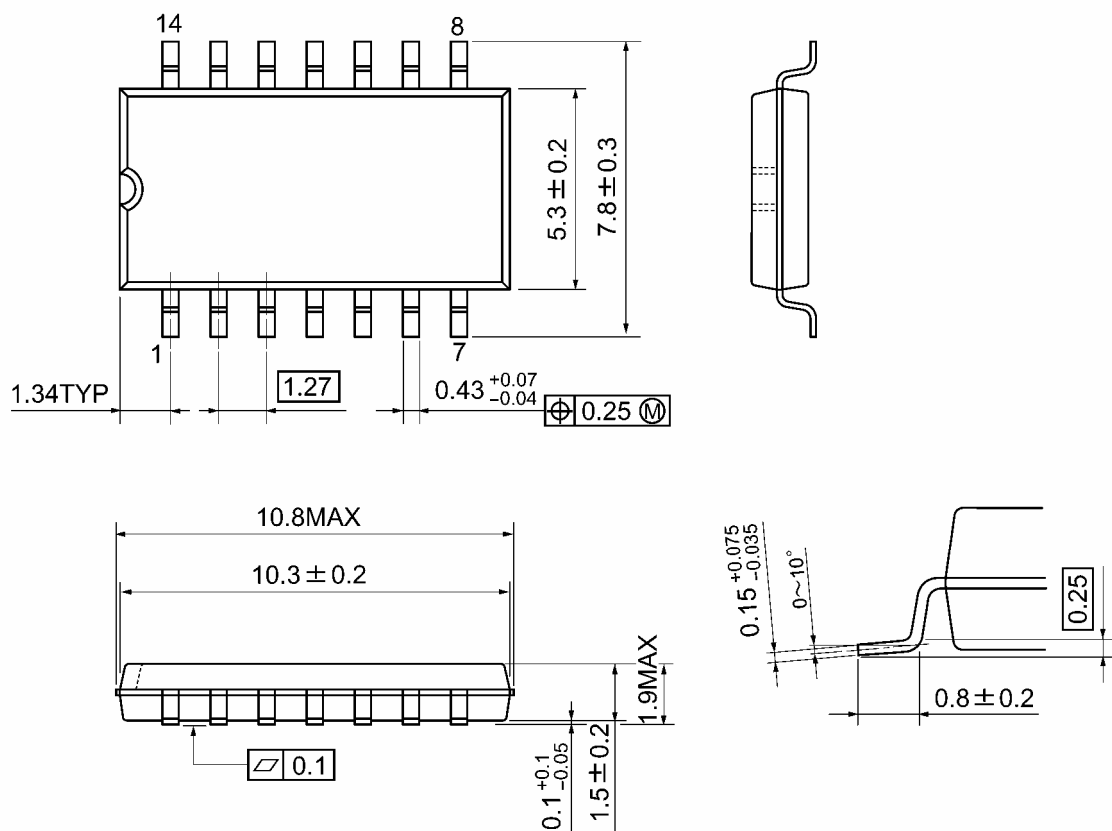


Weight: 0.96 g (typ.)

Package Dimensions

SOP14-P-300-1.27A

Unit: mm

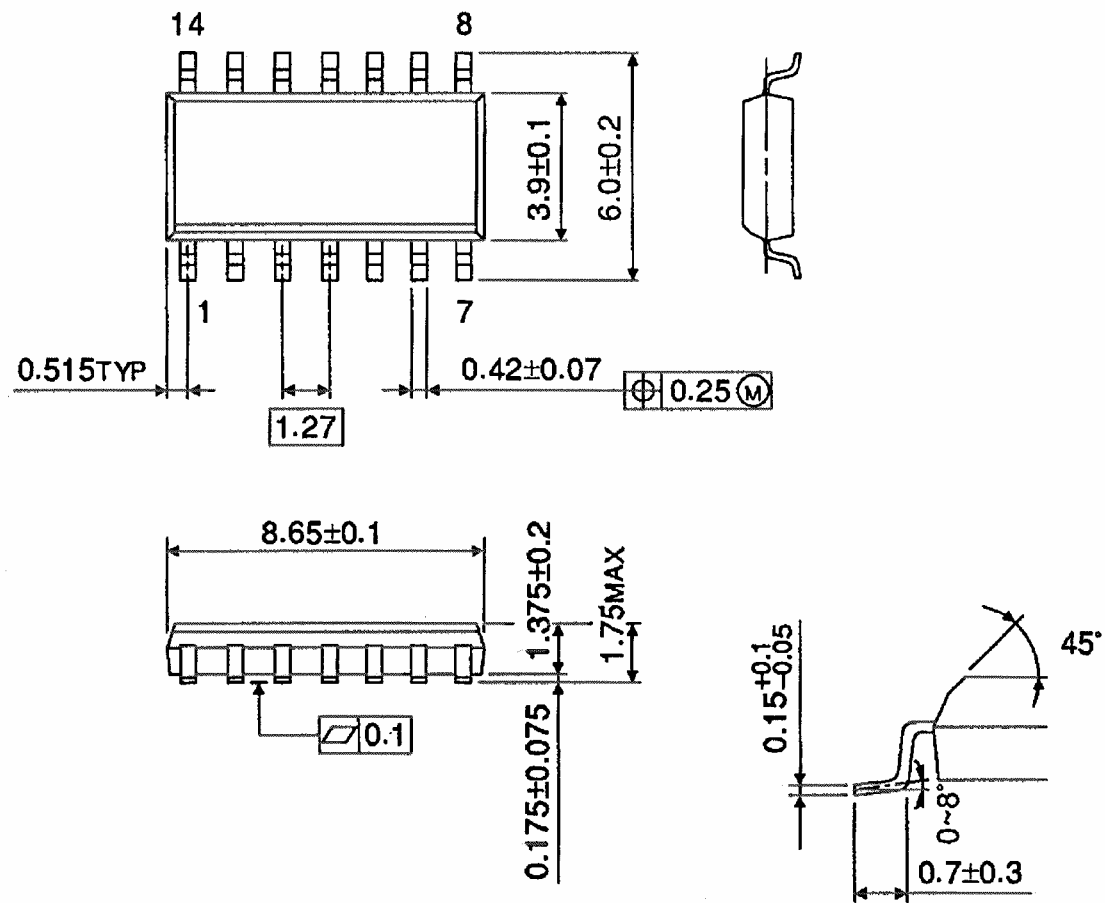


Weight: 0.18 g (typ.)

Package Dimensions (Note)

SOL14-P-150-1.27

Unit : mm



Note: This package is not available in Japan.

Weight: 0.12 g (typ.)

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20070701-EN GENERAL

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